



# ACE12410B

## N-Channel Enhancement Mode Field Effect Transistor

### Features

- $V_{DS} (V) = 20V$
- $I_D = 8A$
- $R_{DS(ON)} = 12.5m\Omega @ V_{GS}=4.5V$
- $R_{DS(ON)} = 16.5m\Omega @ V_{GS}=2.5V$

### General Description

- load switch
- battery protection

### Absolute Maximum Ratings

Parameter		Symbol	Max	Unit
Drain-Source Voltage		$V_{DSS}$	20	V
Gate-Source Voltage		$V_{GSS}$	$\pm 12$	V
Drain Current (Continuous) <sup>*AC</sup>	$T_A=25^\circ C$	$I_D$	8	A
	$T_A=70^\circ C$		6	
Drain Current (Pulse) <sup>*B</sup>		$I_{DM}$	32	
Power Dissipation	$T_A=25^\circ C$	$P_D$	2.8	W
Operating and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	$^\circ C$

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ C$ . The Power dissipation  $P_{DSM}$  is based on  $R_{\theta JA}$  and the maximum allowed junction temperature of  $150^\circ C$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ C$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ C$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J = 25^\circ C$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

### Thermal Resistance Ratings

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient	$t \leq 10s$	$R_{thJA}$	37	45	$^\circ C/W$
Maximum Junction-to-Ambient	Steady State		66	80	

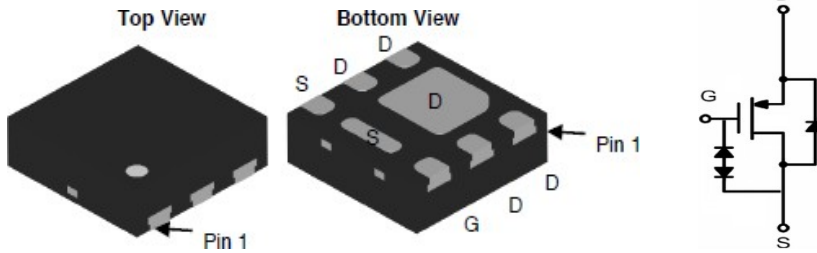


# ACE12410B

## N-Channel Enhancement Mode Field Effect Transistor

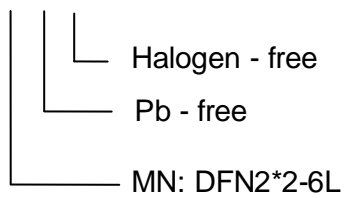
### Packaging Type

DFN2\*2-6L



### Ordering information

ACE12410B XX + H





# ACE12410B

## N-Channel Enhancement Mode Field Effect Transistor

### Electrical Characteristics $T_A=25\text{ }^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	20			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=20V, V_{GS}=0V$			1	$\mu A$
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	0.4	0.75	1.5	V
Gate Leakage Current	$I_{GSS}$	$V_{GS}=\pm 12V, V_{DS}=0V$			$\pm 100$	nA
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=4.5V, I_D=8A$		12.5	15	m $\Omega$
		$V_{GS}=2.5V, I_D=4A$		16.5	20	
Forward Transconductance	$g_{FS}$	$V_{DS}=5V, I_D=8A$		50		S
Diode Forward Voltage	$V_{SD}$	$I_{SD}=1A, V_{GS}=0V$		0.65	1	V
Diode Forward Current	$I_S$	$TC = 25^\circ C$			3.5	A
Switching						
Total Gate Charge	$Q_g$	$V_{DS}=10V, I_D=8A$ $V_{GS}=4.5V$		7		nC
Gate-Source Charge	$Q_{gs}$			1		
Gate-Drain Charge	$Q_{gd}$			2.5		
Turn-On Delay Time	$T_{d(on)}$	$V_{GS}=4.5V, V_{DS}=10V$ $R_L=1.25\Omega, R_{GEN}=3\Omega$		3		ns
Turn-On Rise Time	$t_r$			4.5		
Turn-Off Delay Time	$t_{d(off)}$			28		
Turn-Off Fall Time	$t_f$			6		
Dynamic						
Input Capacitance	$C_{iss}$	$V_{DS}=10V, V_{GS}=0V$ $f=1.0MHz$		782		pF
Output Capacitance	$C_{oss}$			158		
Reverse Transfer Capacitance	$C_{rss}$			98		



# ACE12410B

## N-Channel Enhancement Mode Field Effect Transistor

### Typical Performance Characteristics

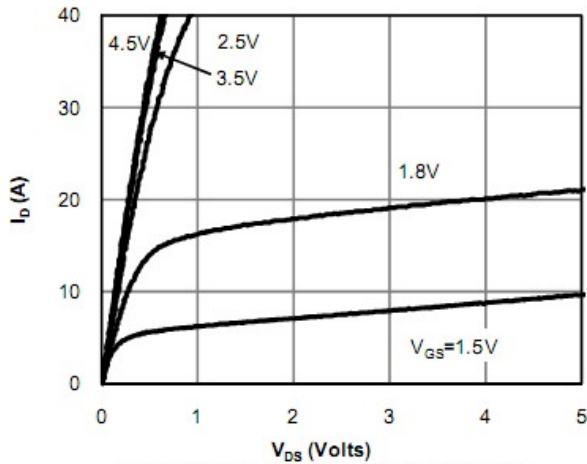


Fig 1: On-Region Characteristics (Note E)

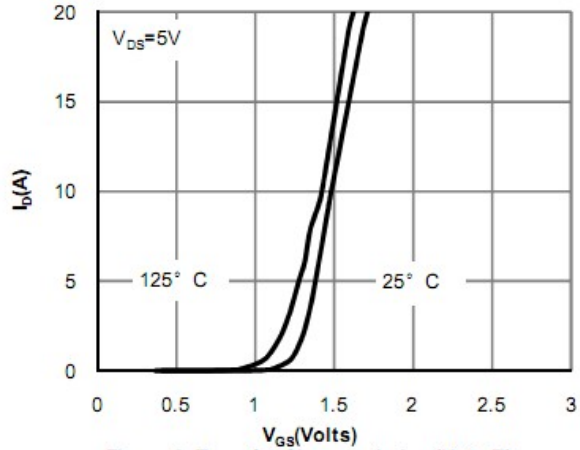


Figure 2: Transfer Characteristics (Note E)

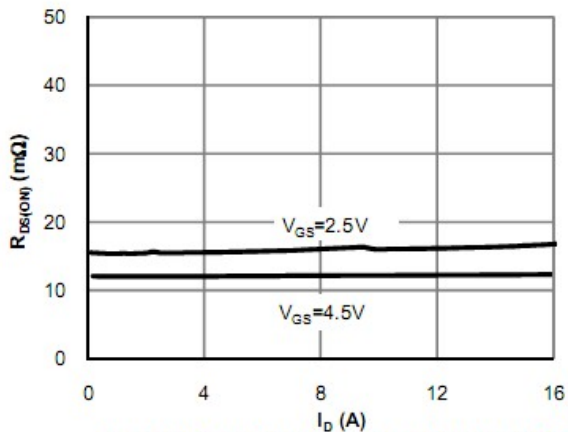


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

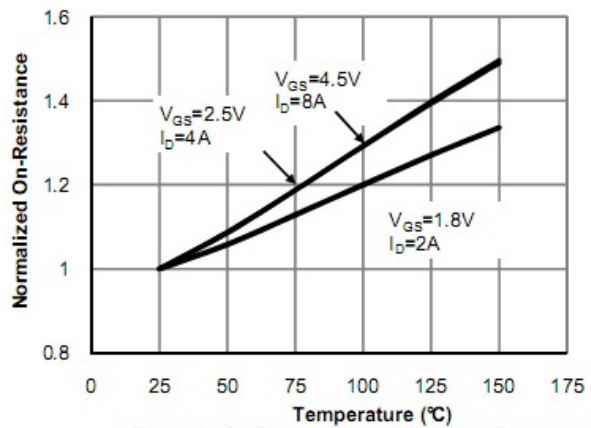


Figure 4: On-Resistance vs. Junction Temperature (Note E)

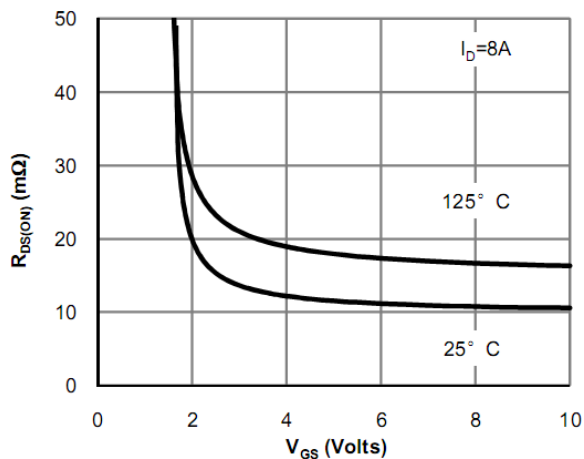


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

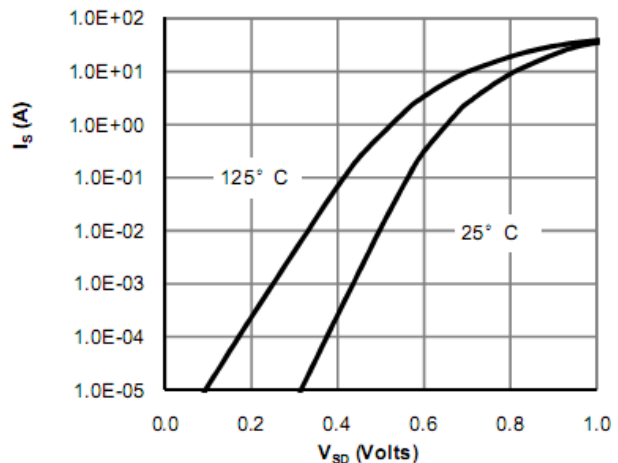


Figure 6: Body-Diode Characteristics (Note E)



# ACE12410B

## N-Channel Enhancement Mode Field Effect Transistor

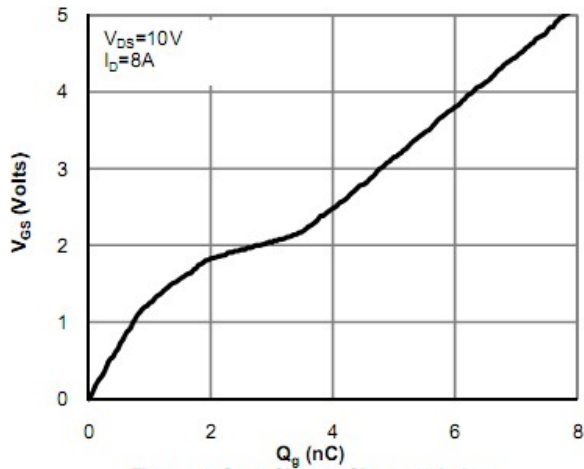


Figure 7: Gate-Charge Characteristics

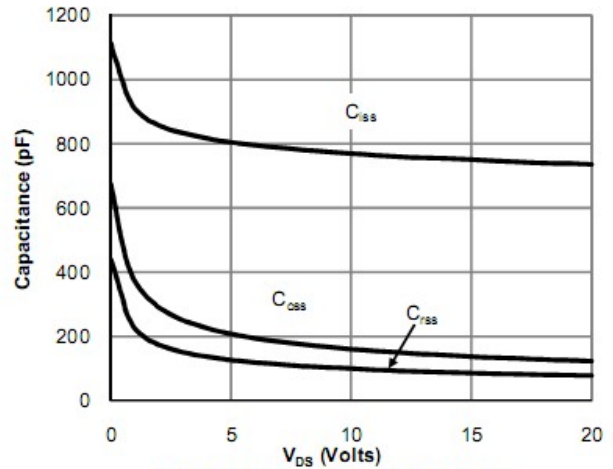


Figure 8: Capacitance Characteristics

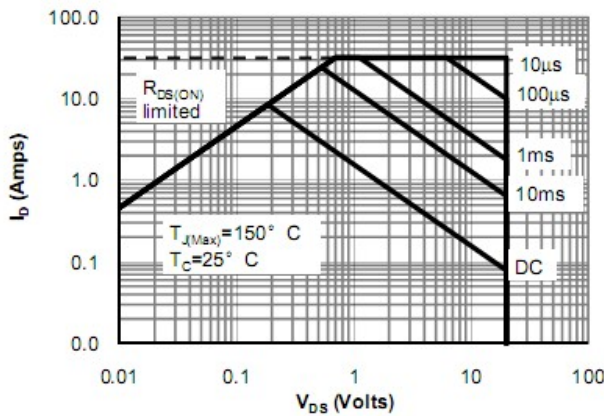


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

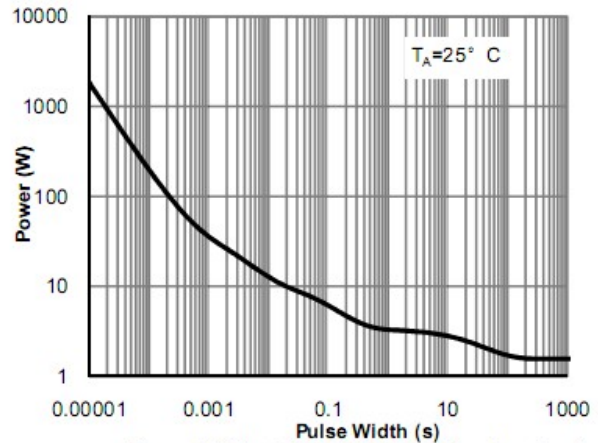


Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note H)

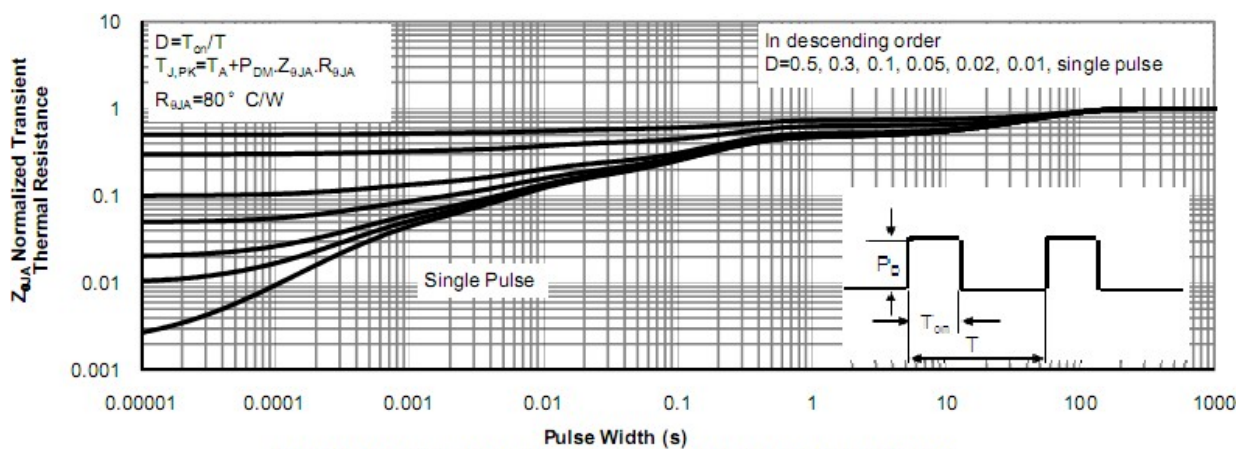


Figure 12: Normalized Maximum Transient Thermal Impedance (Note H)

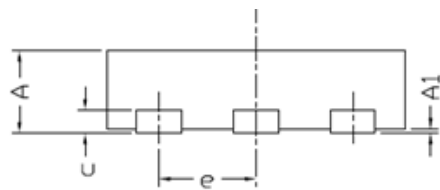
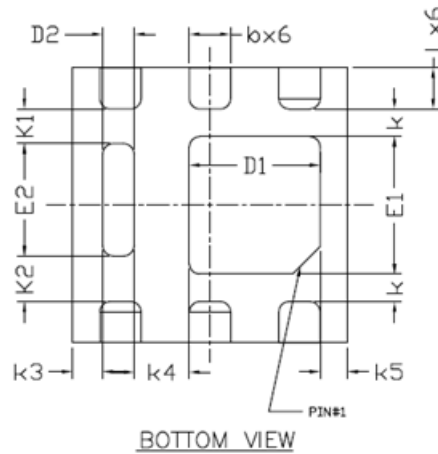
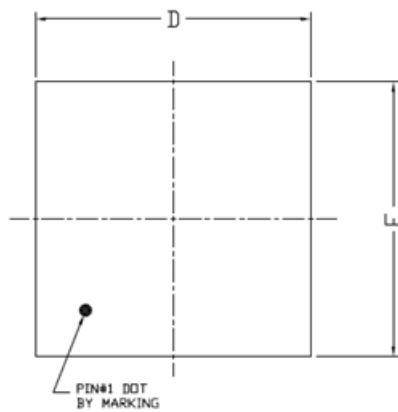


# ACE12410B

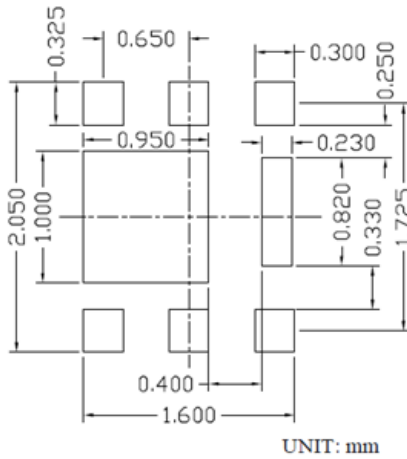
## N-Channel Enhancement Mode Field Effect Transistor

### Packing Information

DFN2\*2-6L



#### RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.50	0.55	0.60	0.020	0.022	0.024
A1	0.00	—	0.05	0.000	—	0.002
b	0.25	0.30	0.35	0.010	0.012	0.014
c	0.152 REF			0.006 REF		
D	1.90	2.00	2.10	0.075	0.079	0.083
D1	0.85	0.95	1.05	0.033	0.037	0.041
D2	0.13	0.23	0.33	0.005	0.009	0.013
E	1.90	2.00	2.10	0.075	0.079	0.083
E1	0.90	1.00	1.10	0.035	0.039	0.043
E2	0.72	0.82	0.92	0.028	0.032	0.036
e	0.65 BSC			0.026 BSC		
K	0.10	0.20	0.30	0.004	0.008	0.012
K1	0.15	0.25	0.35	0.006	0.010	0.014
K2	0.23	0.33	0.43	0.009	0.013	0.017
K3	0.12	0.22	0.32	0.005	0.009	0.013
K4	0.30	0.40	0.50	0.012	0.016	0.020
K5	0.10	0.20	0.30	0.004	0.008	0.012
L	0.25	0.30	0.35	0.010	0.012	0.014

#### NOTE

1. CONTROLLING DIMENSION IS MILLIMETER.  
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



# **ACE12410B**

## **N-Channel Enhancement Mode Field Effect Transistor**

### Notes

ACE does not assume any responsibility for use as critical components in life support devices or systems without the express written approval of the president and general counsel of ACE Electronics Co., LTD. As sued herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.